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The Interlayer Spacing of Graphite

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From a study of well-crystallized graphites direct evidence is obtained of the different spacings between oriented and disoriented layers, respectively, in a stack of parallel graphite layers. It is shown that when the proportion of disoriented layers is small there is practically a linear relation with the mean interlayer spacing deduced from 000*l* lines.

Introduction

Many workers, such as Hofmann & Wilm (1936) and Bacon (1950a), have published information on the variation with crystallite size of the interlayer spacing of graphite. More recently, Franklin (1950, 1951), in studies of both non-graphitic and graphitic carbons, concludes that the measured interlayer spacings are really only mean values. She suggests that to a first approximation the groups of oriented and disoriented layers in a graphitic carbon retain, respectively, the spacings of 3.354 and 3.44 A. which are characteristic of the extreme numbers of the series, namely, highly crystalline graphite and non-graphitic carbon. The first purpose of the present paper is to present more direct evidence in support of this conclusion from measurements with more highly crystalline graphites. It is shown that, in contrast to the variation of interlayer spacing given by 000l lines, there is no variation in the value deduced from hkil lines. Secondly, a further study is made, in the light of Franklin's conclusions, of the variation of the apparent interlayer spacing with the proportion, p, of disoriented layers. It is found that for small values of p there is approximately a linear relation.

Experimental determination of c_{0008} and $c_{11\overline{2}6}$

Measurements were made to determine the spacings of the neighbouring 0008 and $11\overline{2}6$ lines sufficiently accurately to determine whether there existed a significant difference between the values of c, the unitcell dimension, deduced from the two lines. This was attempted for the four samples of graphite (Ceylon graphite and three artificial samples A_1 , A_2 and A_3) used in the writer's earlier work (Bacon, 1950*a*). Accurate determination of spacings from the line positions was made by using, in principle, the method previously described (Bacon, 1948).

In the case of the most crystalline sample, A_3 , the measurement was straightforward. The X-ray specimen was prepared by extrusion, after mixing the sample with diamond to provide a correction curve, and the α_1 , α_2 components of 0008 and 1126 were measured separately on a standard film-measuring instrument.

For the Ceylon graphite the $11\overline{2}6$ line had already become too diffuse for complete resolution of the α_1, α_2 components and the line was therefore microphotometered and resolved graphically by the method discussed by Pease (1948). On the other hand, the 0008 line was too weak for accurate estimation of position by photometry and was determined with the filmmeasuring instrument, measurement of the neighbouring diamond lines 400 and 331 being made by both methods in order to correlate the readings from the two instruments. With the third sample, A_2 , increasing diffuseness made it necessary not only to use both methods of measurement but also to use a solid, turned specimen in order to avoid the additional background produced by the diamond and the gum tragacanth binder. In this case a small spacing correction was estimated from the position of the $12\overline{3}0$ graphite line. and correlation between the two instruments was achieved by measuring the positions of razor-blade scratches drawn on the film. It was finally concluded that this particular sample represented the extreme to which such methods could be applied. With A_1 , the least crystalline of the samples used in the earlier work, the 0008 and $11\overline{2}6$ lines were too diffuse for accurate measurement.

In Fig. 1 values of c_{0008} derived from the above measurements are shown together with those previously reported for the same samples. The two sets of results are within the experimental error, except for sample A_2 , where the new results seem to be slightly lower. This may be a genuine difference, showing an increase in the proportion of disoriented layers when a sample is powdered, as has already been noticed (Bacon, 1950b). Also shown in Fig. 1 are the values of the cdimension calculated from the spacing of the $11\overline{2}6$ planes, using also the value of the a dimension known from the previous work (1950a). The abscissa is the average thickness, t, for which, according to the Hofmann & Wilm (1936) model of graphite layer stacking, the layers are stacked regularly in proper orientation. The values of t are those previously determined from line-width measurements.

It is concluded from Fig. 1 that, in contrast to the variation shown by c_{0008} , the value of $c_{11\overline{2}6}$ is constant,

at least to a first approximation. The former, of course, depends on the mean interlayer spacing of a stack of parallel layers, some oriented and others disoriented, and Méring (1949) has shown that in the case of a random distribution of two closely similar spacings the value of $\frac{1}{2}c$ deduced from the peak of a 000*l* line will, in fact, equal the mean interlayer spacing in the stack. On the other hand, $c_{11\bar{2}\bar{6}}$ refers only to the interlayer spacing within an oriented group.



Fig. 1. Comparison of c spacings derived from 0008 and $11\overline{2}6$.

Measurement of proportion of disoriented layers

In her second paper, Franklin (1951) presents in detail the evidence for believing that the distribution of disoriented layers in a parallel stack of graphite layers is random, rather than approximately regular as is assumed in the Hofmann & Wilm model. Over the whole range of graphitic carbons she chooses the relationship $d=3.440-0.086(1-p^2)$

to give the mean interlayer spacing in terms of p, the proportion of disoriented layers. This is a parabolic curve having zero slope when p=0, i.e. for very perfect graphite, which is at variance with the writer's conclusion (Bacon, 1950a) that, on the Hofmann & Wilm model, there is a linear variation of c with 1/t, or p, near the origin. The disagreement is not due to the assumption of regular, rather than random, errors in the layer stacking, for it can be deduced, most conveniently by comparison of the formula given by Wilson (1949, p. 76, equation (29)) with that given by the writer (1950a, p. 138), that the form of the curve near the origin of 1/t or p is the same on whichever model the line widths are interpreted. Moreover, the experimental curve drawn by Franklin (1950) is practically linear at the origin. In order to confirm

Correction for geometrical broadening

a random distribution of disoriented layers.

The determination of the values of p was made by comparison of the line shapes of $11\overline{24}$ and $11\overline{26}$ in reciprocal space with those given by the intensity formula 1 II_2

$$I = \frac{1 - U^2}{1 + U^2 - 2U\cos\phi},\tag{1}$$

where $\phi = \pi l$, l being the crystallographic index, and U=1-p. For the $11\overline{2}l$ lines this is deduced from the more general formula given by Hendricks & Teller (1942). In the case of the well-crystallized samples which are being considered the effect of geometrical broadening on the calculated line shapes is appreciable, and in order to minimize errors as far as possible this was allowed for empirically. The geometrical broadening was measured using the 331 diamond line, which occurs very close to the 11 $\overline{2}6$ graphite line, and it was found that the shape of this line in reciprocal space was very closely approximated by the function

$1/(1+7500\omega^2)^2$,

where ω is the increment of the *l* index away from the $11\overline{2}6$ position. The curves given by (1) for various values of p were accordingly corrected analytically by the above function (for this analysis the writer is indebted to Dr J. Howlett). The corrected curves for a number of values of p are shown as the full lines in Fig. 2, on which are also shown the measured experimental curves for the three samples A_3 , Ceylon and A_2 . The figure shows the good agreement of shape between the experimental curves and those calculated. Further, the curve for A_2 , for example, can be contrasted with the chain dotted curve which is of equal half-width but of the form $\sin^2 k\omega/(k\omega)^2$, corresponding to a regular. rather than random, distribution of disorientations in a parallel stack of graphite layers. The width of the diamond 331 line used for determining the geometrical broadening is about half of the width of the sharpest curve drawn in Fig. 2.

With the least crystalline sample, A_1 , for which p is about 0.2, the $11\overline{2}6$ line was too diffuse for accurate measurement and $11\overline{2}4$ was employed. In this case sodium fluoride was used as a standard substance, the geometrical broadening being given by its conveniently situated 420 and 422 lines. Similar agreement between the observed and calculated shapes of the $11\overline{2}4$ line was obtained.

In all cases the line profiles obtained by photometry were initially analysed graphically into their α_1 , α_2 components.

Discussion of results

Fig. 3 shows the results of the re-interpretation for the four well-crystallized graphite samples, covering the

range 0-0.2 in p, together with Franklin's results up to a value of 0.6 in p. It is felt that the two sets of results are in good agreement and are best represented by the full-line curve, practically linear at the origin, rather than by the broken parabola which gives the less than $\frac{1}{2}k'$, i.e. the spacing between a disoriented layer and an oriented group is rather nearer to that of a pure disoriented structure than to that of a pure oriented structure. With increase of p the gradual change from (2) to (3) may be due to a reduction of the



Fig. 2. Line shapes in reciprocal space for 1126. Comparison of experimental results with theoretical curves corrected for geometrical broadening.



Fig. 3. Variation of mean interlayer spacing with p. — experimental curve; $\dots d = 3.440 - 0.086 (1-p) - 0.086p (1-p);$ $\dots d = 3.440 - 0.086 (1-p) - 0.064p (1-p).$

best fit to Franklin's results as p increases to unity. The form of the relation near the origin is well approximated by the chain dotted curve whose equation is

$$d = 3.440 - 0.086 (1 - p) - 0.064 p (1 - p), \qquad (2)$$

in contrast to the parabola, which can be written

à

$$l = 3.440 - 0.086 (1 - p) - 0.086 p (1 - p).$$
(3)

This means that Franklin's k'' (1951, p. 259) is rather

spacing for disorientations which are next but one to an oriented group. This has previously been neglected, Franklin having made the simplifying assumption that a group of oriented layers reduces the spacing only of the first disoriented layer immediately on either side of it. When p is small the frequency of occurrence of two adjacent disorientations is small, so that (2) would apply; with increase of p more successive disoriented layers will appear and if, as seems likely, there is a slight shortening of the second disorientation spacing, then a change towards (3) would take place. The probability of occurrence of two adjacent disorientations is equal to $p^2(1-p)$ and it is, in fact, found that improved agreement over an increased range of p can be obtained by adding a further term, $0.03p^2(1-p)$, to the right-hand side of (2).

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The a dimension of graphite. By G. E. BACON, Atomic Energy Research Establishment, Harwell, Didcot, England, and R. E. FRANKLIN, Wheatstone Physics Laboratory, King's College, London W.C. 2, England

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It was previously reported (Bacon, 1950) that accurate measurements of the position of the $(12\overline{3}0)$ line for different graphites indicated an apparent slight variation of the *a* dimension. At the same time, however, measurements of the $(12\overline{3}1)$ line gave a constant *a* value, suggesting that, in accordance with theoretical work (Bradburn, Coulson & Rushbrooke, 1948), the true *a* dimension, for this range of graphites, is constant.

The anomalously low values of a obtained from the (hki0) lines can be explained in exactly the same way as the displacement shown by Warren (1941) to occur in the maxima of the (hk) bands in random-layer structures. All the graphites examined in the work referred to above were imperfectly crystalline, the degree of disorder between neighbouring layers being such that the intensity of (hki0) reflexions in reciprocal space always falls off much less rapidly along the c^* axis than perpendicular to it. This is illustrated in Fig. 1, which shows schematically the reciprocal space in the neighbourhood of an (hki0) point.

The case of the least-crystalline sample, A_1 , of those previously measured may be considered semi-quantitatively. The breadth of the $(11\overline{2}0)$ line leads to an estimated layer diameter, b, of 1500 A. (although the line broadening is too small for this to be determined accurately). The shape of the $(11\overline{2}4)$ line for this sample is in agreement with the hypothesis (Franklin, 1951) of a random distribution of oriented and disoriented layers, and indicates a fraction 0.2 of disorientations (Bacon, 1951). Using these figures it is found that the intensities of the streak at Q_0 and Q (Fig. 1) have fallen only to 90 and 83% of the intensity at the equator. Consequently, the displacement of the maximum of the $(11\overline{2}0)$ line will be almost as large as for a random-layer structure having layers of the same diameter. Warren (1941) shows that the displacement in the latter case is such that the difference between the true and apparent spacings is given by

$$\Delta d = d \, \frac{0 \cdot 16\lambda}{b \, \sin \, \theta},$$

where d is the true spacing. Applying this equation to the $(11\overline{2}0)$ line of the sample A_1 , we find that the



difference between the true and apparent values of the lattice parameter, a, is 0.0007 A. This is exactly equal to the experimental difference between the apparent a values given by the (1120) lines of A_1 and of a much more highly crystalline graphite, A_3 (Bacon, 1950).

The precise agreement is, of course, fortuitous, but it

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